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U.S. UTILITY Patent Application

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PATENT DATE

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APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/880584	D	438	715	1762 1183	644/dga Zervig

APPLICANTS

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TITLE

Method for minimizing the critical dimension growth of a feature on a semiconductor wafer

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PTO-523
1983

U.S. PATENT OFFICE	RECEIVED	NOTICE OF ALLOWANCE MAILED
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